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○- Home
○- What Can
    I Access?
○- Log-out

Tables of Contents

○- Journals
    & Magazines
○- Conference
    Proceedings
○- Standards

Search

○- By Author
○- Basic
○- Advanced
○- CrossRef

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○- Establish IEEE
    Web Account
○- Access the
    IEEE Member
    Digital Library

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○- Access the
    IEEE Enterprise
    File Cabinet

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JNL = Journal or Magazine   **CNF** = Conference   **STD** = Standard

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